Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/724,717	SU, WEN-WEI	
Examiner	Art Unit	
John A. Tweel, Jr.	2636	

SEARCHED					
Class	Subclass	Date	Examiner		
340	539.11	6/7/2005	JAT		
	514	6/7/2005	JAT		
	605	6/7/2005	JAT		
	603	6/7/2005	JAT		
702	188	6/7/2005	JAT		
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AII	0 63803	secret	VAI		
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All	o lessos	seonld	JA1		
All	o lessas	seonld	JAI		
All	o lessas	seonld	JAI		
A((o lessas	seonld	JAI		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
340	539.11	10/12/2005	JAT		
-	603	10/12/2005	JAT		
	605	10/12/2005	JAT		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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